



# Hybrid Quality Issues for Present LHC Trackers: The CMS Example...



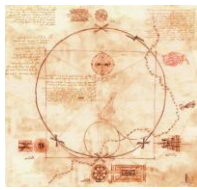
November 2011

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The CMS Example

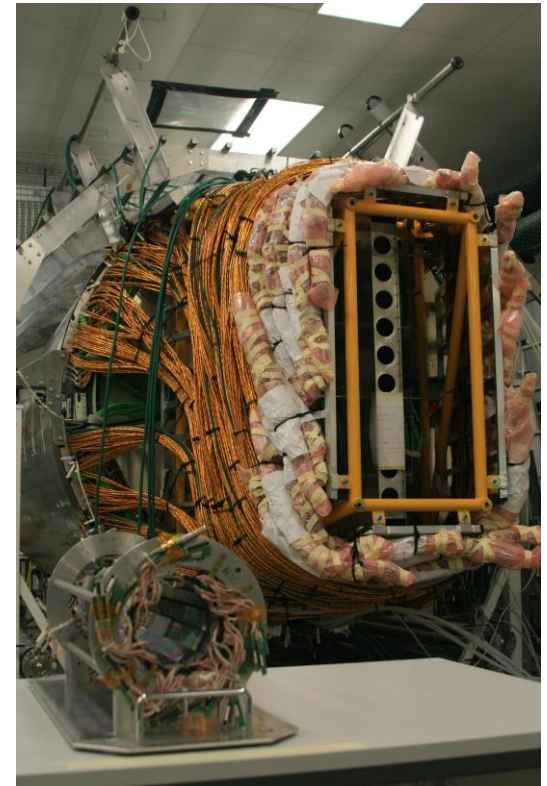
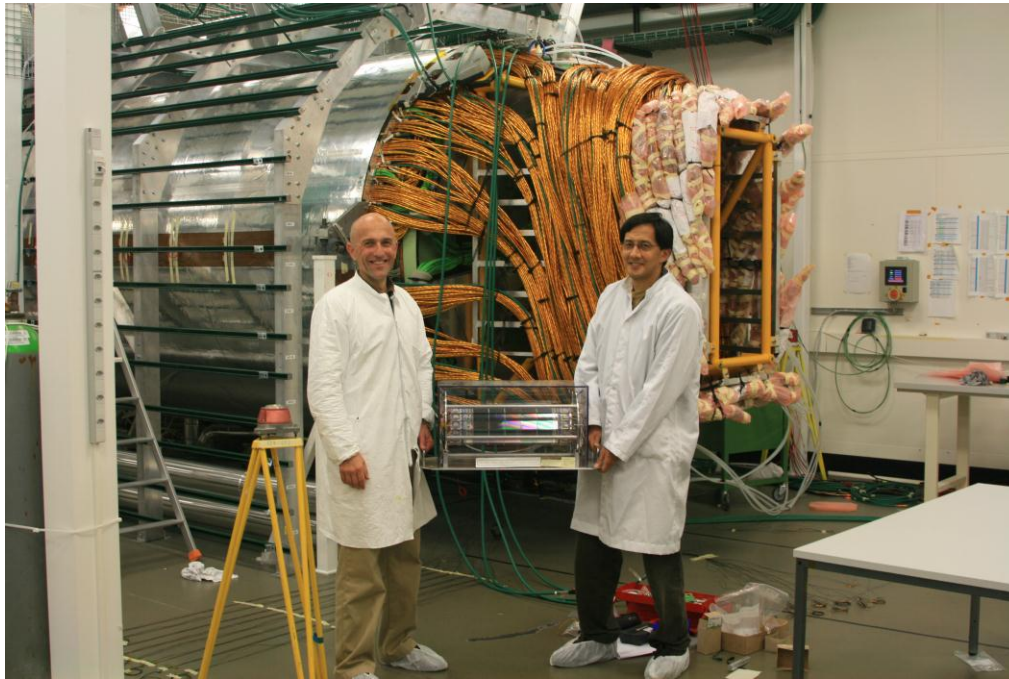
Marcello Mannelli



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- **The Trackers of the Atlas and CMS Experiments, in particular, represent the largest ever deployment of Silicon Strip Sensors**
  - ~ 2 orders of magnitude larger than LEP Vertex Detectors
  - ~ 1 order of magnitude larger than CDF / D0 Inner Trackers



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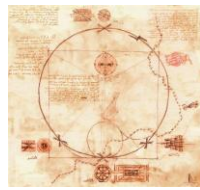
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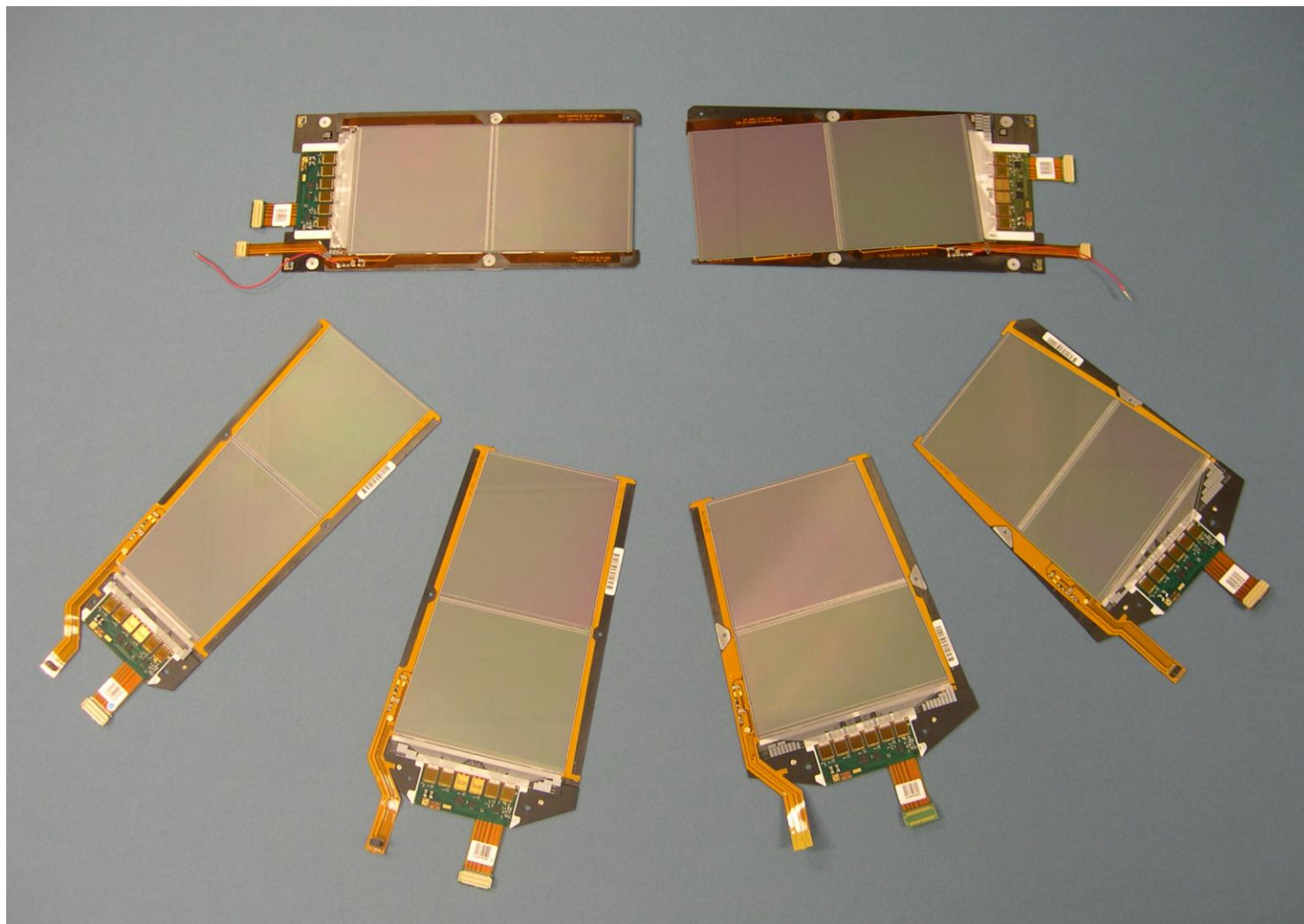


## Hybrid Quality Issues for Present LHC Trackers: The CMS Example...



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    - ~ 2 orders of magnitude larger than LEP Vertex Detectors
    - ~ 1 order of magnitude larger than CDF / D0 Inner Trackers
  - **The CMS Tracker is instrumented with some 17'000 Silicon Strip sensor Modules, with an active area of about 200m<sup>2</sup>**
    - Previous Silicon detectors typically had a hundreds of (smaller) modules
  - **This required a much higher level of Industrialization and Automation of Production Assembly and Testing, from individual components to complete Modules**
- ⇒ **Much more emphasis on Quality Management and Quality Assurance**
- In addition to Quality Control
  - To ensure BOTH High Quality and High Throughput

## A Selection from the CMS Module Menu

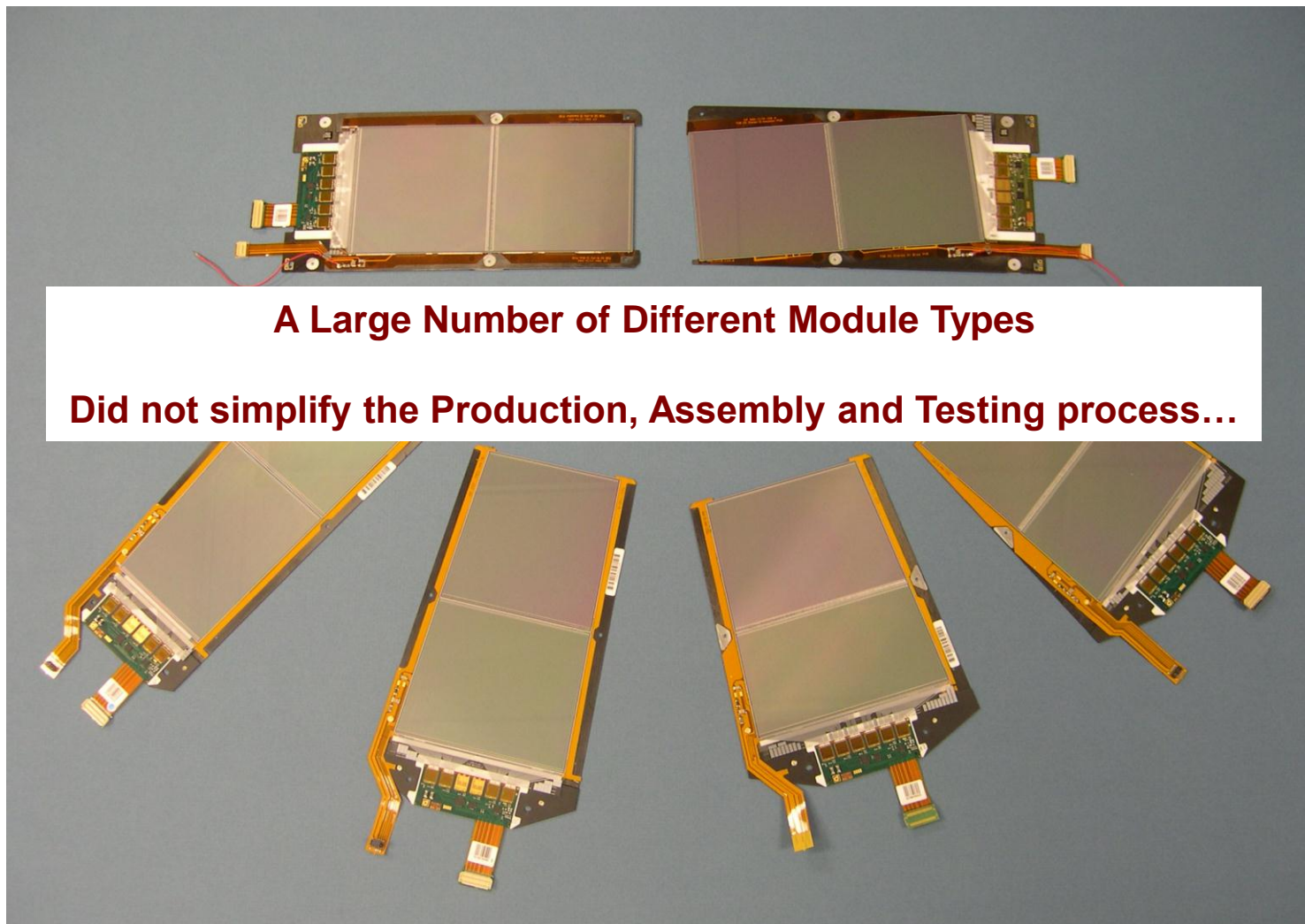
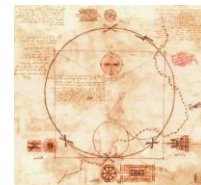


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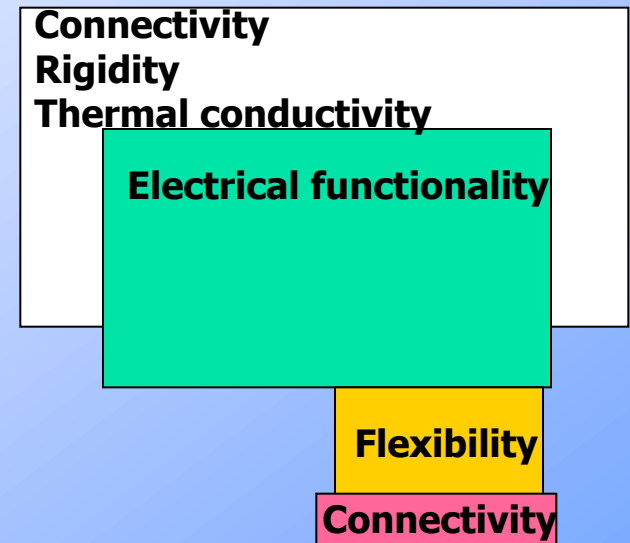


**A Large Number of Different Module Types**

**Did not simplify the Production, Assembly and Testing process...**

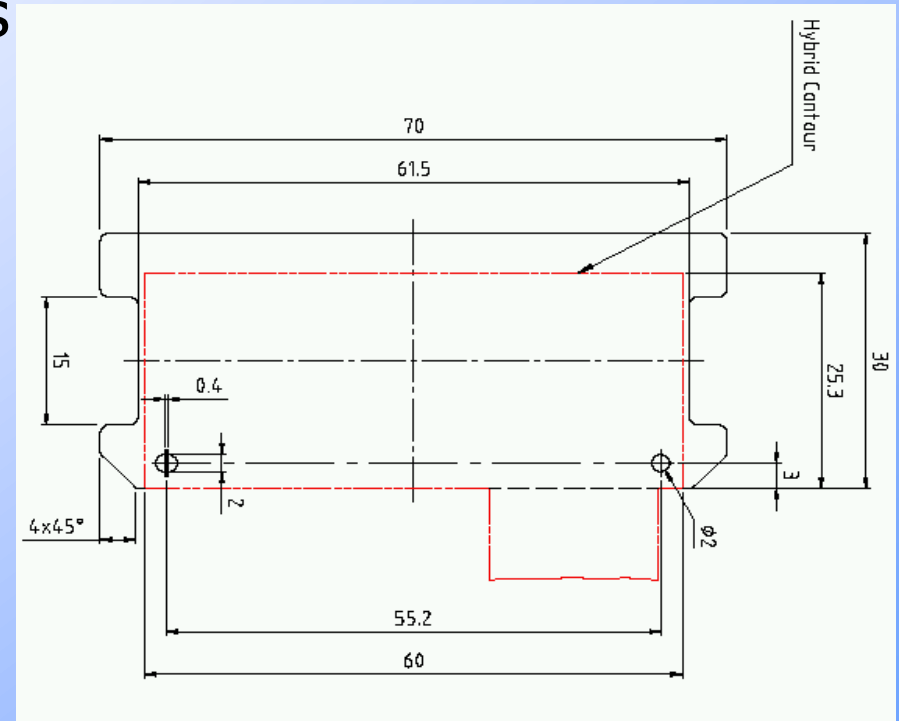
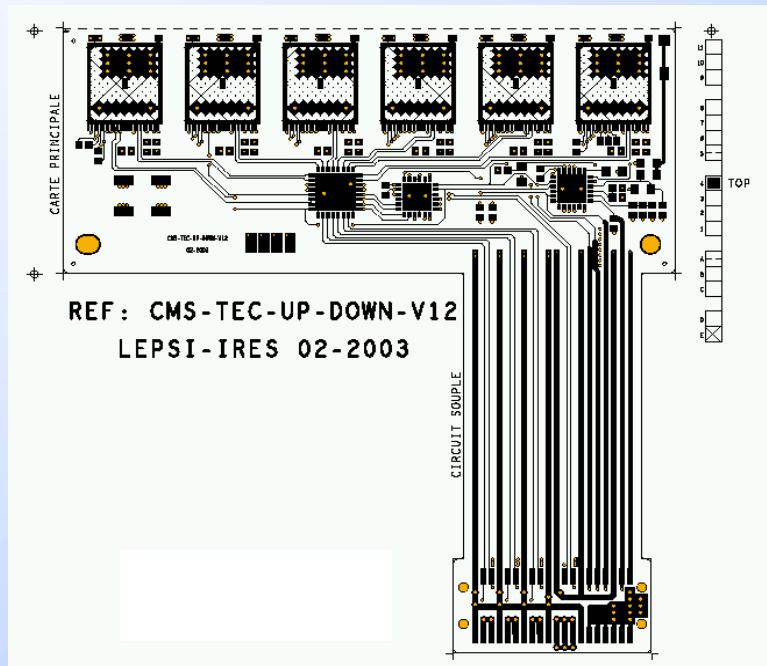
# ***The CMS Tracker Front End Hybrid***

- Multiple functions
  - Electrical
  - Mechanical
  - Thermal
- Multiple constraints
  - Interface to pre-defined elements
    - Mechanical
    - electrical
  - Reworkable
  - Low mass
  - High reliability
  - Cheap
- Perceived as low profile, soft glue element



# *The Hybrid Layout*

- 120 $\mu\text{m}$  min feature size
- Up to 768 electrical channels
- 17500 pcs





# *The Finished Hybrid*





# History

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- Several technologies investigated
  - Thick film ceramic
  - FR4
  - Flex/Rigid
  - Flex
- Several teams with several opinions
- CMS-Tracker eventually converges on Flex solution
  - Project late start in 2002
  - Few companies involved
    - Design becomes technology driven
  - Chips and mechanics already frozen or well advanced
    - Constraints are hard
- Several design change requests from users
  - Resulting in several flavors and several modifications
- Several difficulties at production start
  - Technological
    - Circuit
    - Assembly
  - Organizational

# Organizational difficulties

CMDFV	12-Jul-05		TOB																								TIS												TEC												TOTALS			BATCH ID																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																																
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## ■ 12 hybrid variants

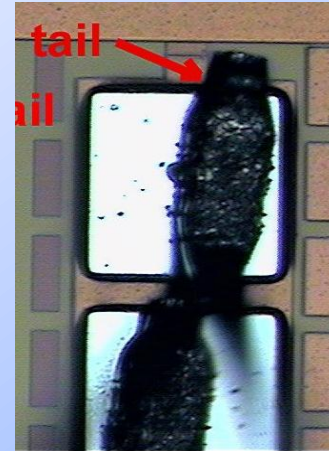
- transform a high volume production into a multi-batch logistic nightmare
- Complex delivery schedule
- All variants needed simultaneously
- Difficult stock build up and management
- Management of ancillary hardware becomes problematic (boxes, adapter cards, etc...)

## ■ heterogeneous CMS community

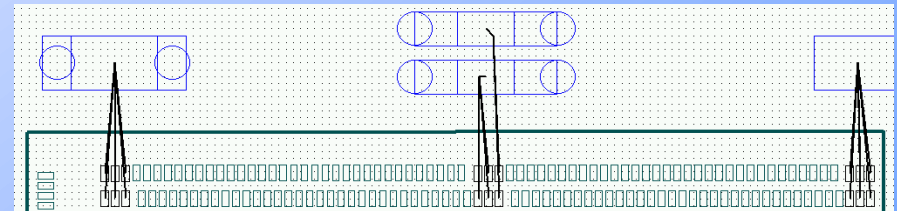
- Unclear internal definition of responsibilities
- Multiple interfaces to company
- Incompatibility between academic and industrial ways

# *Technological difficulties, assembly*

- Bonding
  - chip pad structure optimized for ball bonding
  - Unsuitable chip pad size
  - Irregular pad quality on circuit (and on chip?)
  - Special dicing requirement
- Large effort to optimize and maintain bonding quality, several production stops



- Mixed bonding at company and CERN
  - Chip loading accuracy  $\pm 22\mu\text{m}$
  - No globe top possibility
- Long term bond adherence is a prime concern
- ASIC LPCC Package difficult to inspect
  - No boundary scan possibility
- Detailed analysis of all functional test results required





# *Technological difficulties, circuit*

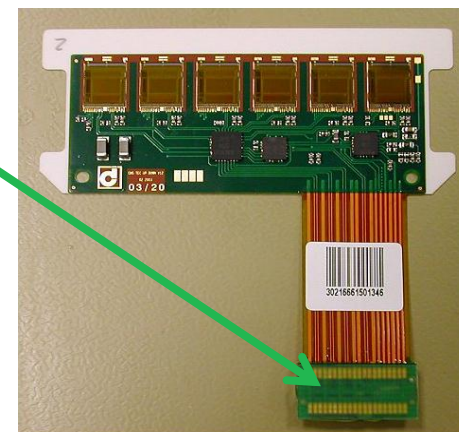
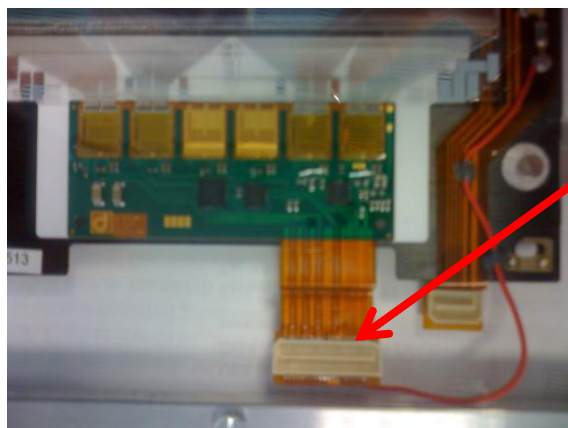
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- Metal on flex
- Lamination on ceramic
- Via metallization
  - Hidden defect
- Fast production / Slow QA feedback
- Irreversible addition of value when mounting hybrid on sensor module
- Large effort to recover

## Recognizing the Tip of an Iceberg



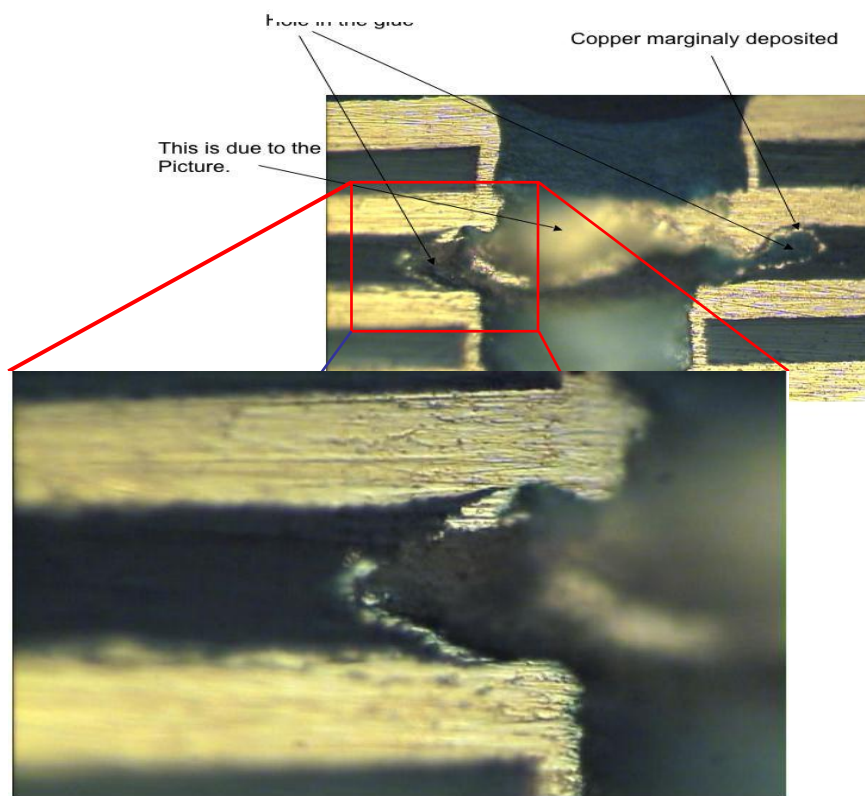
- **A first, potentially serious problem:**  
**Fragile solder joints from the Flex Cable to the Connector**
  - The problem was not seen in the Qualification phase
  - But became apparent as soon as hybrids were handled, connected & disconnected for Testing
  - Production was interrupted, and resumed after re-qualification of hybrids with a stiffener behind the connector which resulted in robust assembly



# Recognizing the Tip of an Iceberg



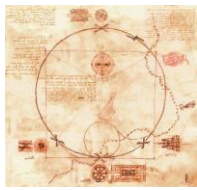
- **A second, Far More Serious Problem:  
Fragile Via Metallization**







# Recognizing the Tip of an Iceberg



- **A second, Far More Serious Problem:  
Fragile Via Metallization**
- **What made this problem Potentially Fatal was that**
  - The vast majority of vias had an electric contact and the Hybrids were initially fully functional
    - As a result, the problem was not seen during the Qualification phase, and only became apparent once a small number of initially good hybrid failures were scrutinized in detail
  - The vias, however, were fragile and a large fraction would inevitably fail with time
    - All hybrids produced with this process had to be rejected, and all modules assembled with these hybrids were un-useable!
  - By the time the problem was fully recognized, some 8'000 hybrids had already been produced, and many modules assembled with them
    - The impact on the schedule was about a year
    - And the financial impact amounted to several % of the overall cost of the Silicon Strip Tracker



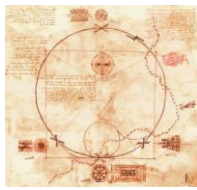
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    - All hybrids produced with this process had to be rejected, and all modules assembled with these hybrids were un-useable!
- **As bad as this was, it could have been A Lot Worse!**
  - Had this very small rate of apparent failures not been immediately acted upon and recognized for what it was, the Iceberg could have sunk us



## Steering the Project back onto a safe course



- **“A good QA plan should avoid bad surprises before getting to this point”**
  - What went wrong?
  - Quality improvement
- **Improve Organizational Structure**
  - Strengthen Hybrid Project Management
  - Clarify and Formalize lines of Communication between CMS and Suppliers
- **Analyze cause of via process failure, and identify a solution**
- **Establish QC protocols for prompt quality feed-back at each process and assembly step**
  - Reduce reliance on delayed feed-back at end of long process pipe-line
  - Ensure All relevant quality parameters are Identified and Controlled
    - Test structures etc.
- **A Cautious and deliberate re-Qualification and re-Start of Production**



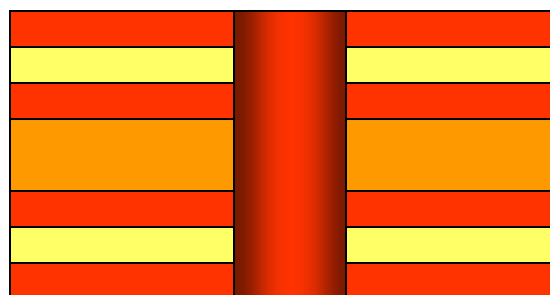
# Steering the Project back onto a safe course



**Original**



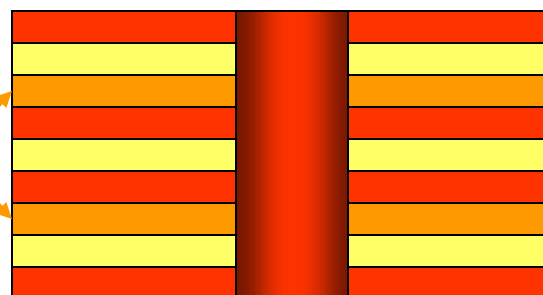
**Improved**



**PI Core**

**Adhesive**

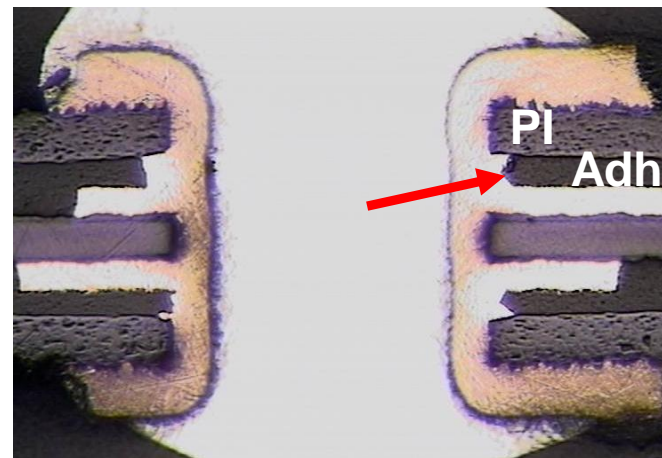
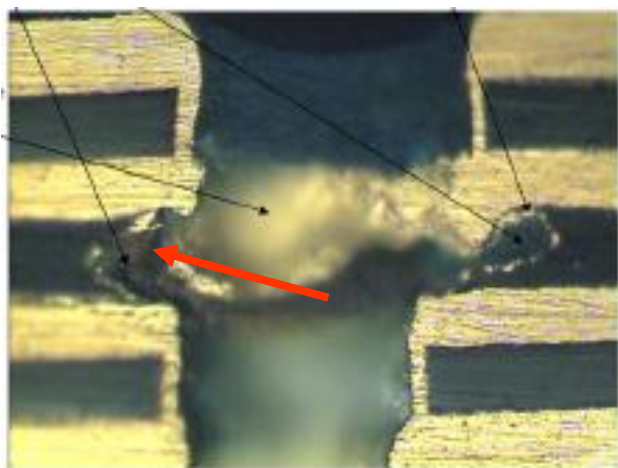
**PI Core**



**PI**

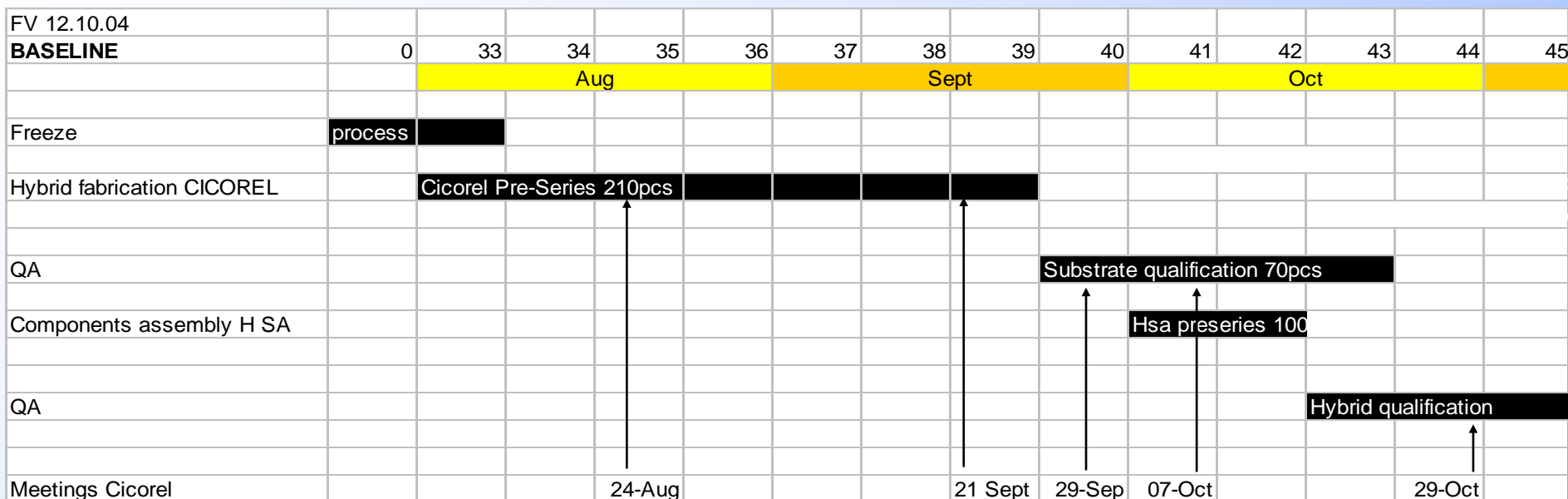
**PI Core**

**PI**



**Test Structures with daisy-chains on 2'800 Vias implemented  
and Systematically Controlled for each plate**

# Qualification Schedule



- 3 Quality Audits (29Sep Cicorel, 7Oct Cicorel, 29Oct H SA)
- Substrate Qualification (Strasbourg and CERN)
- Populated Hybrid Qualification (Strasbourg and CERN)

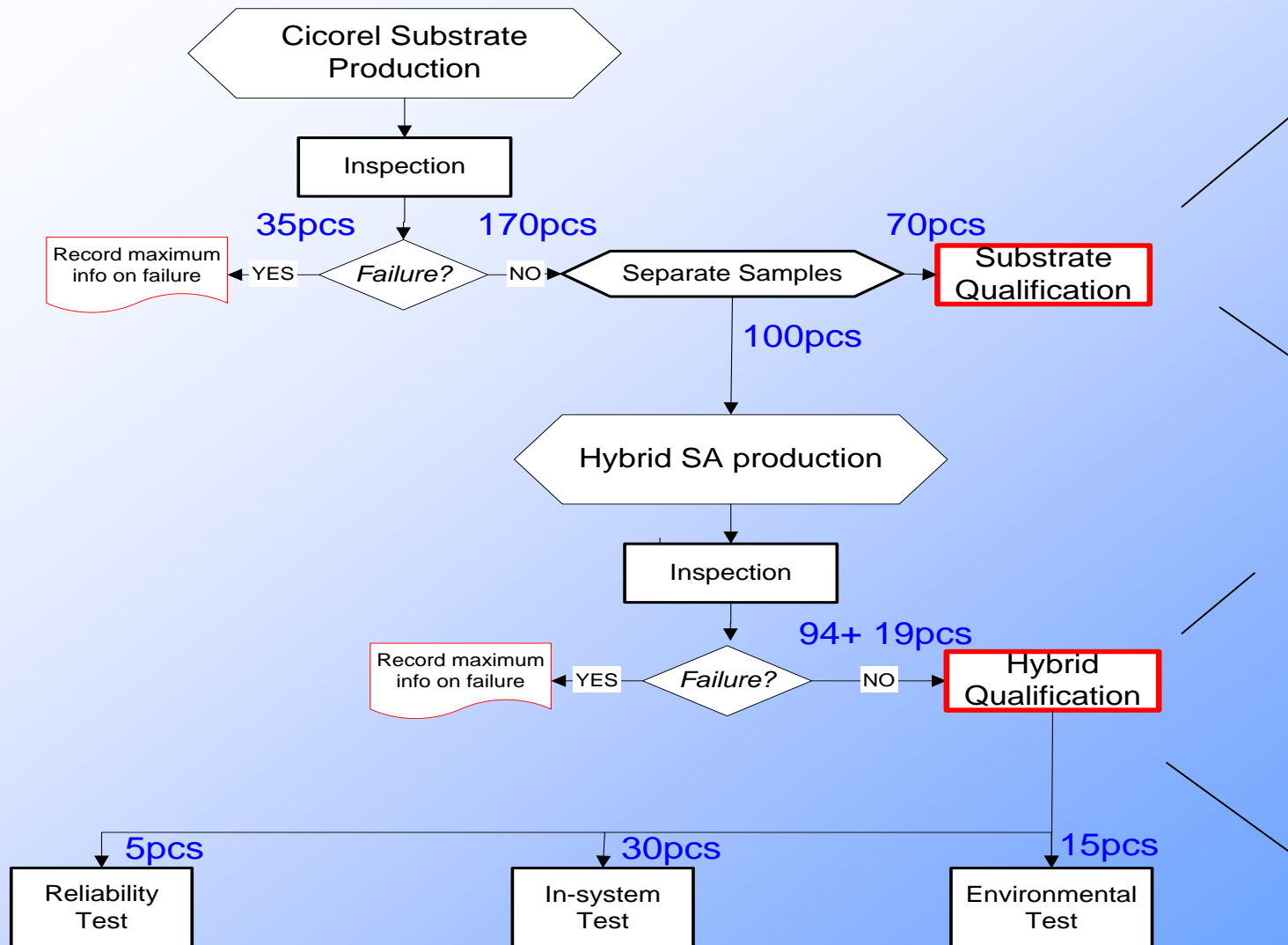
# *Quality Audits (2xCicorel, 1x H SA)*

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- Process flow and control points reviewed and frozen
- Specification and control pass/fail criteria synchronized
- Documentation defined
  - Passed AND failed devices documented
- Device traceability achieved
  
- CMS qualification procedure defined, documented and presented

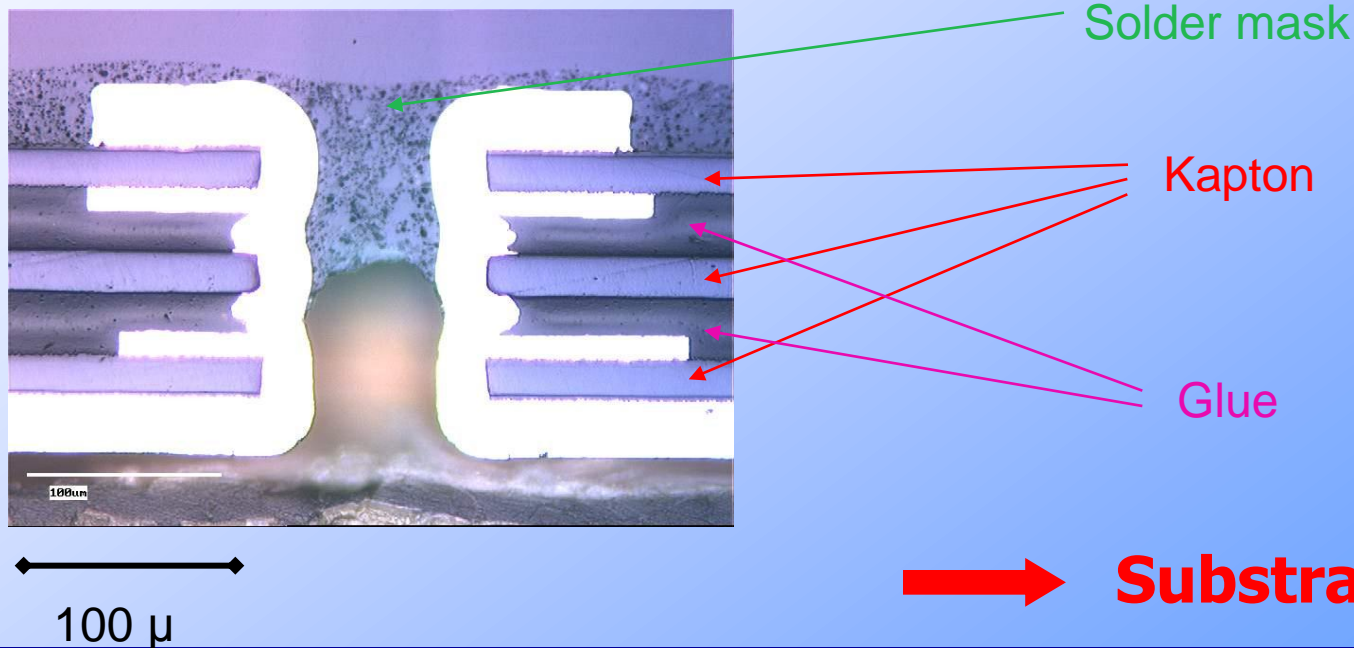


# Qualification flow



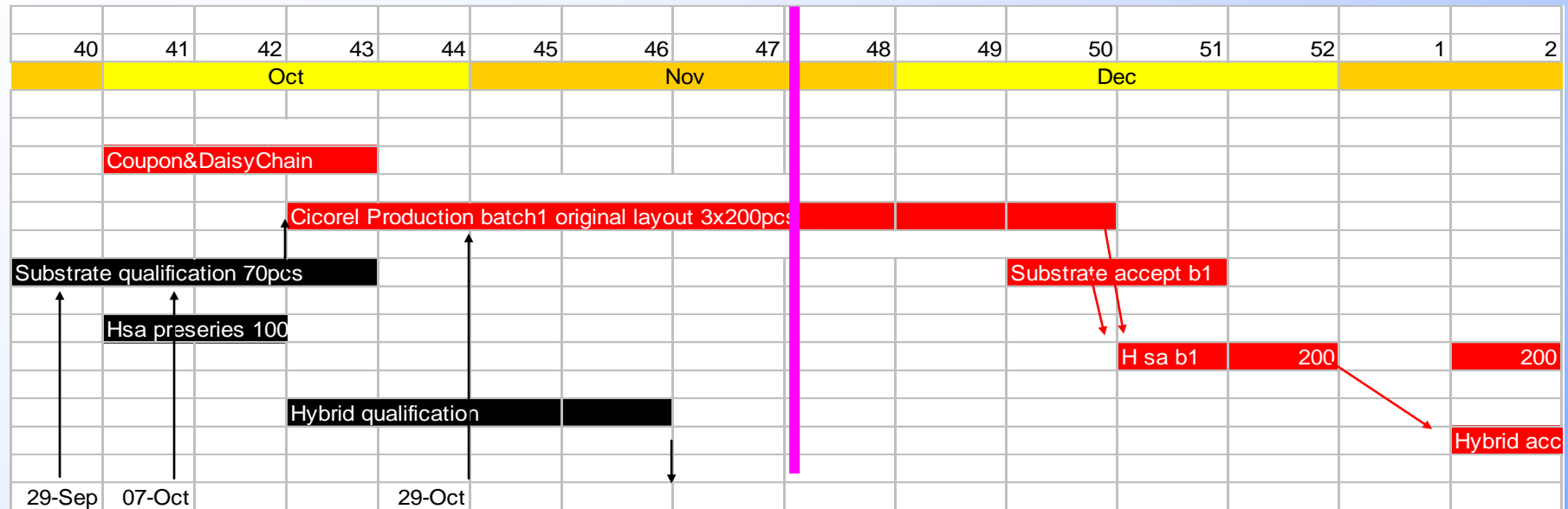
# ***Substrate qualification***

- The only problems found were a minor thickness uniformity problem, presence of foreign material on a bondpad, a small zone of poorer quality bondability, and the presence of rather large metal bumps on some pieces. The latter two should be surveyed closely in upcoming pieces from the same batch and from future batches.
- All other measurements and checks showed very good overall quality and the results within specifications.



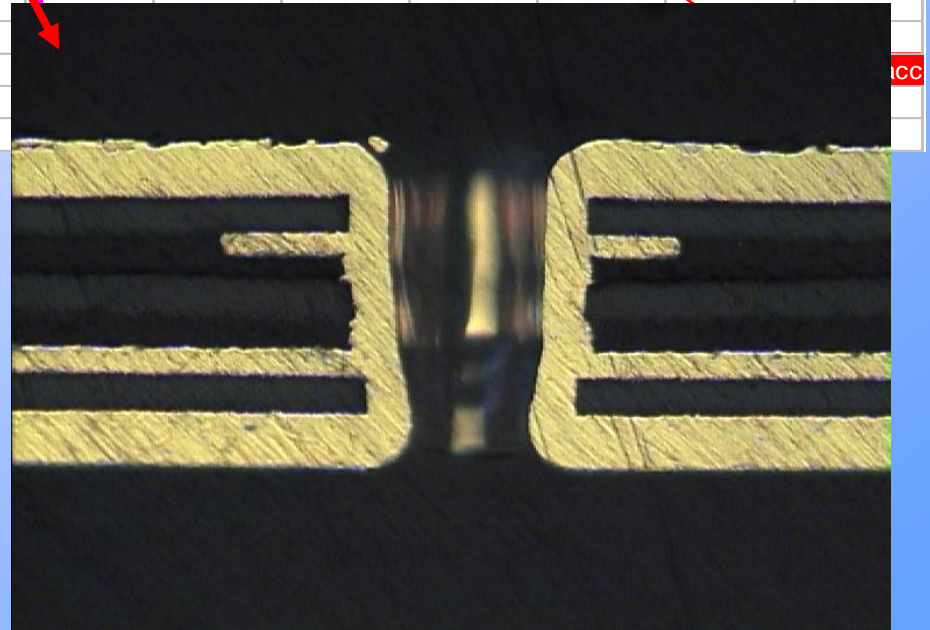
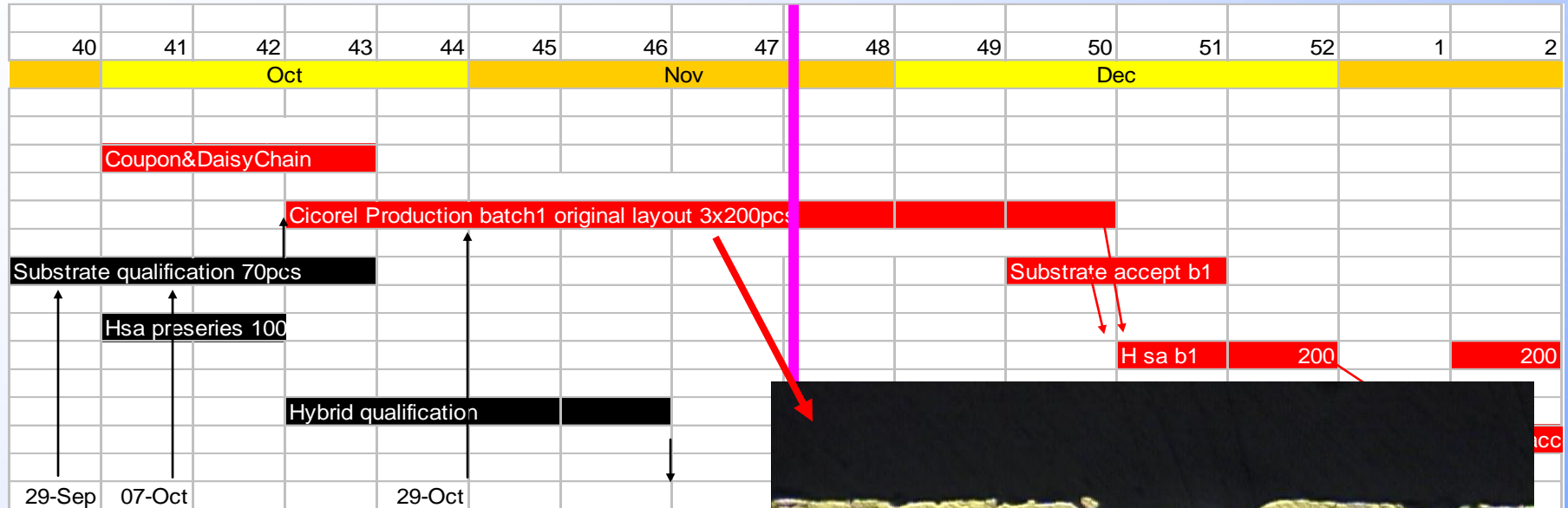
**➡ Substrate qualified**

# FEH Production: a) Cautious Re-Start



- Small production batch b1 launched based on substrate qualification
- Original layout (120um vias) plus test coupon and daisy chain
- 10 weeks turnaround time
- Deliveries are Known Good Hybrids
- Throughput is half expected final capacity
- TOB, TIB and TEC types

# FEH Production: a) Cautious Re-Start



- Vias from b1 successfully metallized

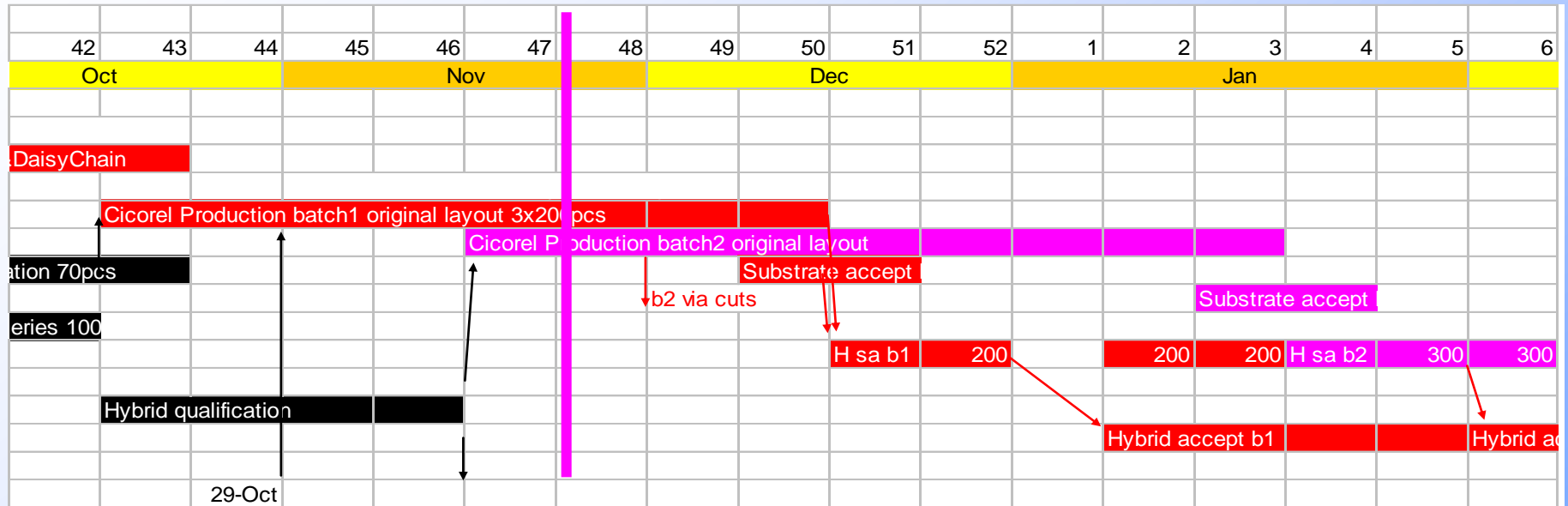


# Hybrid Qualification

- Overall the quality of component loading and bonding was good and comparable to the previously delivered batches with the exception of the bonding quality problems noted below.
- The LPCC (PLL, MUX and DCU) chips have poor soldering aspects. This is due to poor chip packaging and could be a long-term QC issue (reliability).
- None of the failed hybrids in the electrical (FHIT) test was found to be attributable to either Cicorel or H SA
- Bondfoot deformation on APVs found to be large. Slightly reduced bond pull strength averages and significantly larger RMS, especially for upper APV control bonds. Many low strength wires found. **This result does not pass the bonding specifications.**
- 20 unloaded circuits kept aside at CERN were given to HSA for a test of improved bonding quality. These were loaded, bonded. 19 good pieces were delivered to CERN.
- **Results of the 2nd try show improved quality (just passes specifications)** although further improvements would be desirable. The bonding quality will need to be monitored more closely than in the past.

**➡ Hybrid qualified, coaching will be required**

# *FEH production: b) Ramp up*



- Production batch b2 launched based on hybrid qualification
- Throughput limited by Cicorel to 300KGH/week
- ~10% contingency built-in (300-350KGH)
- Discussion on capacity increase in January
- TOB TIB TEC distribution matching construction schedule and priorities



# Conclusion

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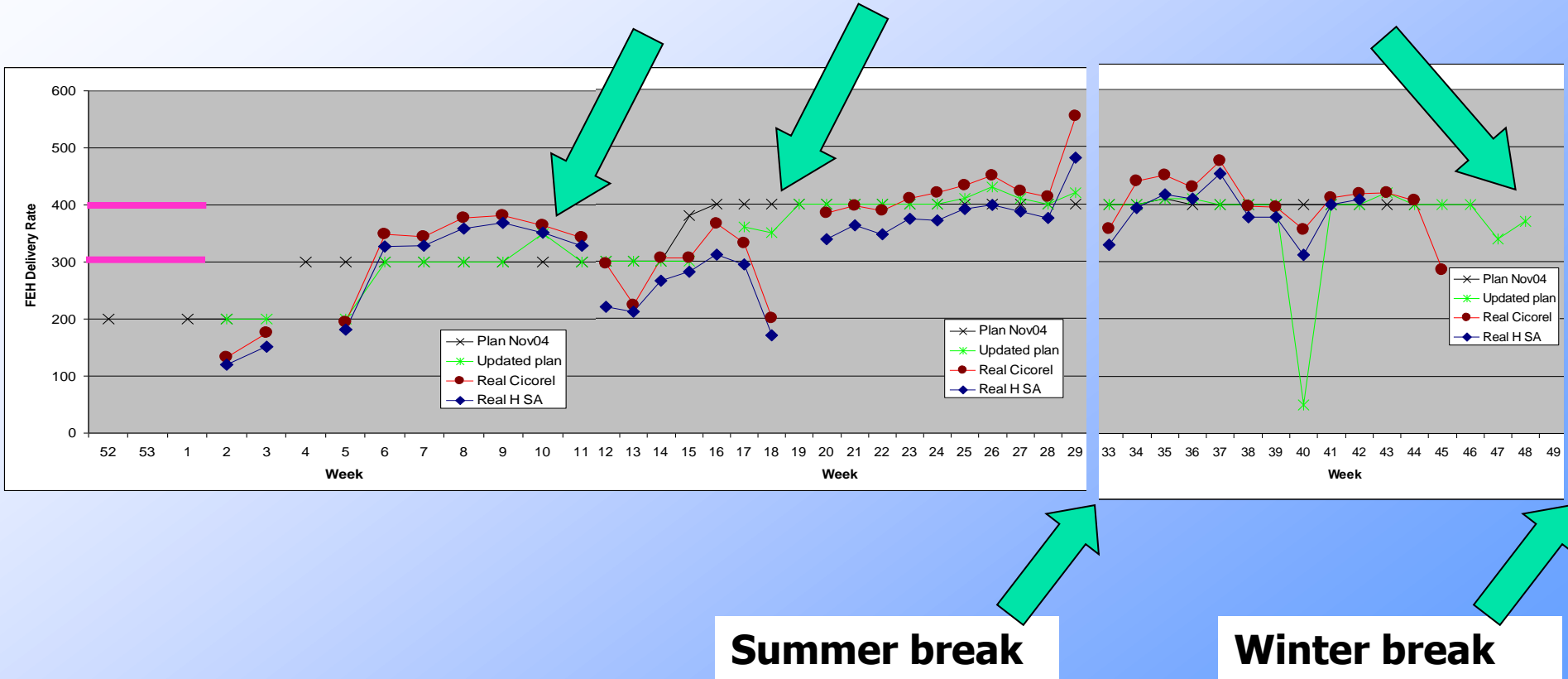
- Process under control at Cicorel
- Quality control and Quality assurance implemented
- Documentation available at:
  - EDMS FE-Hybrid Electronics: CMS-0000008151
- Qualification
  - Substrate: complete
  - Populated hybrid: partially complete
    - Long term tests on-going
    - Module-level tests on-going
- Production re-launched
  - Low speed delivery in January
  - Ramp up in February
- Major effort from all parties (incl. Industry)
- Still a long way to go
  - last delivery Nov 05
- Past still haunting us
  - Need to build confidence and stability
  - Need to settle commercial claim

# Weekly H SA deliveries

**Quantity drop**

**Delivery stop**

**Production End**

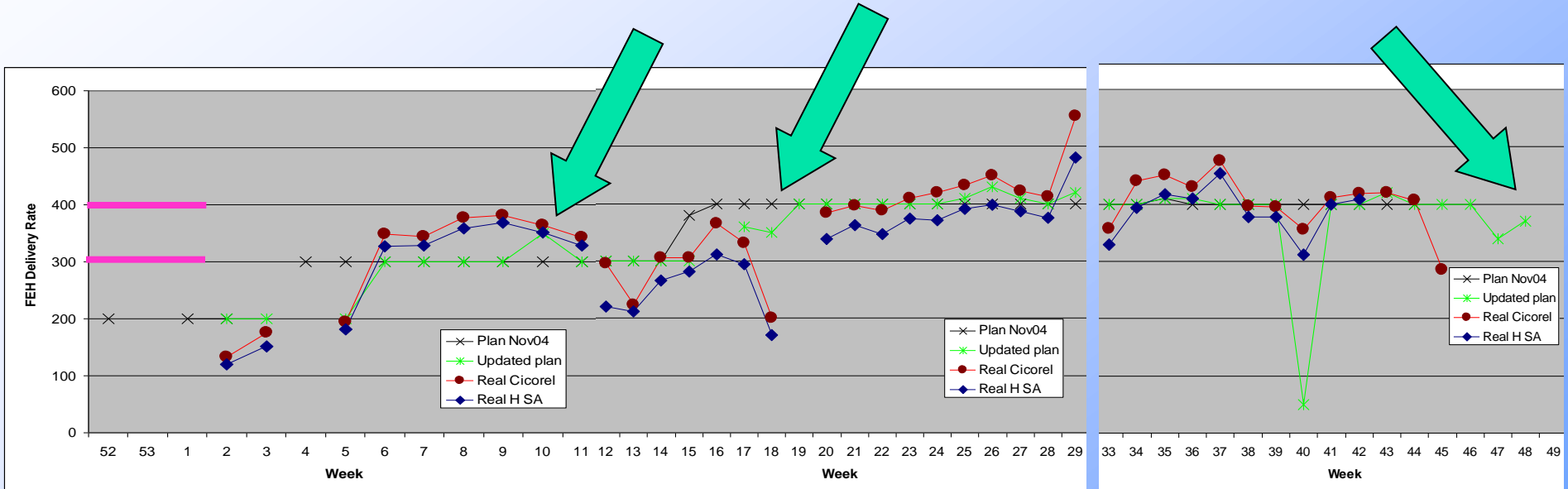


# Weekly H SA deliveries

**Quantity drop**

**Delivery stop**

**Production End**



**OUFF...**

**Summer break**

**Winter break**





# ***CMS Tracker Hybrid Experience: a user and a manufacturer perspective***

- A User:

Francois Vasey, CERN 1211 Geneva 23 [francois.vasey@cern.ch](mailto:francois.vasey@cern.ch)

On behalf of the CMS collaboration

- A Manufacturer:

Hans Wyss, CICOREL [hwyss@cicorel.ch](mailto:hwyss@cicorel.ch)

Anne-Sophie Golsong [agolsong@cicorel.ch](mailto:agolsong@cicorel.ch)



# ***User recommendations***

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- **Hybrids must be part of system level design from the start**
  - Define and advertise hybrid related constraints early
  - Include hybrid experts in system-level discussions
- **Hybrids for large scale detectors must be designed for volume manufacturability, not for cutting edge performance**
  - Avoid state of the art technology
  - Add margin wherever possible
  - Limit variants
- **Hybrids must be designed for testability, with direct feedback possibility to production process**
  - Include panel-level test structures and chip-based test schemes
- **Production ramp up must be slow and allow full qualification**
  - Count on multiple steps from development to production
- **QA and QC must be robust with rapid feedback possibility**
  - Manufacturer and user QA schemes must be synchronized
- **Organizational structure must be clear and well defined.**
  - Members of the structure must trust each other and communicate frequently.

# Manufacturer Recommendations

- Technology driven projects should involve early, a team of experts, where each step of realization and manufacturing are represented.  
Research-Development (with different industries)-  
Product management-Testing-Implementation.
- Define a team with a project leader, open and multi skills
- Always think best case, worst case. Find agreement with all parties involved.
- Be aware that a theoretical solution needs an industrializing expertise and consideration

# Manufacturer Recommendations

- Consider intermediary Quality controls in manufacturing processes (quick failure reactions, statistics, preventive actions)
- Consider time for prototypes and corrective actions before definitive launch
- Guarantee base material continuity standard
- Maintain constant communication and working teams

- Work together with a competent partner
- **Get PCB manufacturer involved at an early stage**
- Share application and utilization of PCB
- Follow design rules and discuss possible areas of concern (reduce risk)
- Learning cooperation
- Allow enough time for prototype and design review
- Use dual sourcing or dual lot strategies



- Risk assessment

- What manufacturing processes are limiting?
- Are multiple suppliers available? (2nd Source)
- Are special materials used? (lead time)
- Is the supply chain covered?
- Invest time in ramp readiness!
- Share information with supplier!

**→ Can be Contradictory to Tender Process**

# Workshop on Quality Issues in Current and Future Silicon Detectors

## What elements of QA are important in a project?

In the past: select some elements as considered useful for our QA planning

Typical project life cycle:

- Concept
- R&D

Design for Quality

Risk analysis

"Sys

Reliab

**"Only the Paranoid Survive..."**

- Testing
- Installation
- Commissioning
- Operation

Quality Control

What went wrong?  
Quality Improvement

*A good QA plan  
should avoid bad  
surprises before  
getting to this  
point*

Increased complexity, cost and long-term reliability required of silicon detectors imply a need to consider all these elements in QA planning.



# Hybrid Quality Issues for Present LHC Trackers: The CMS Example...

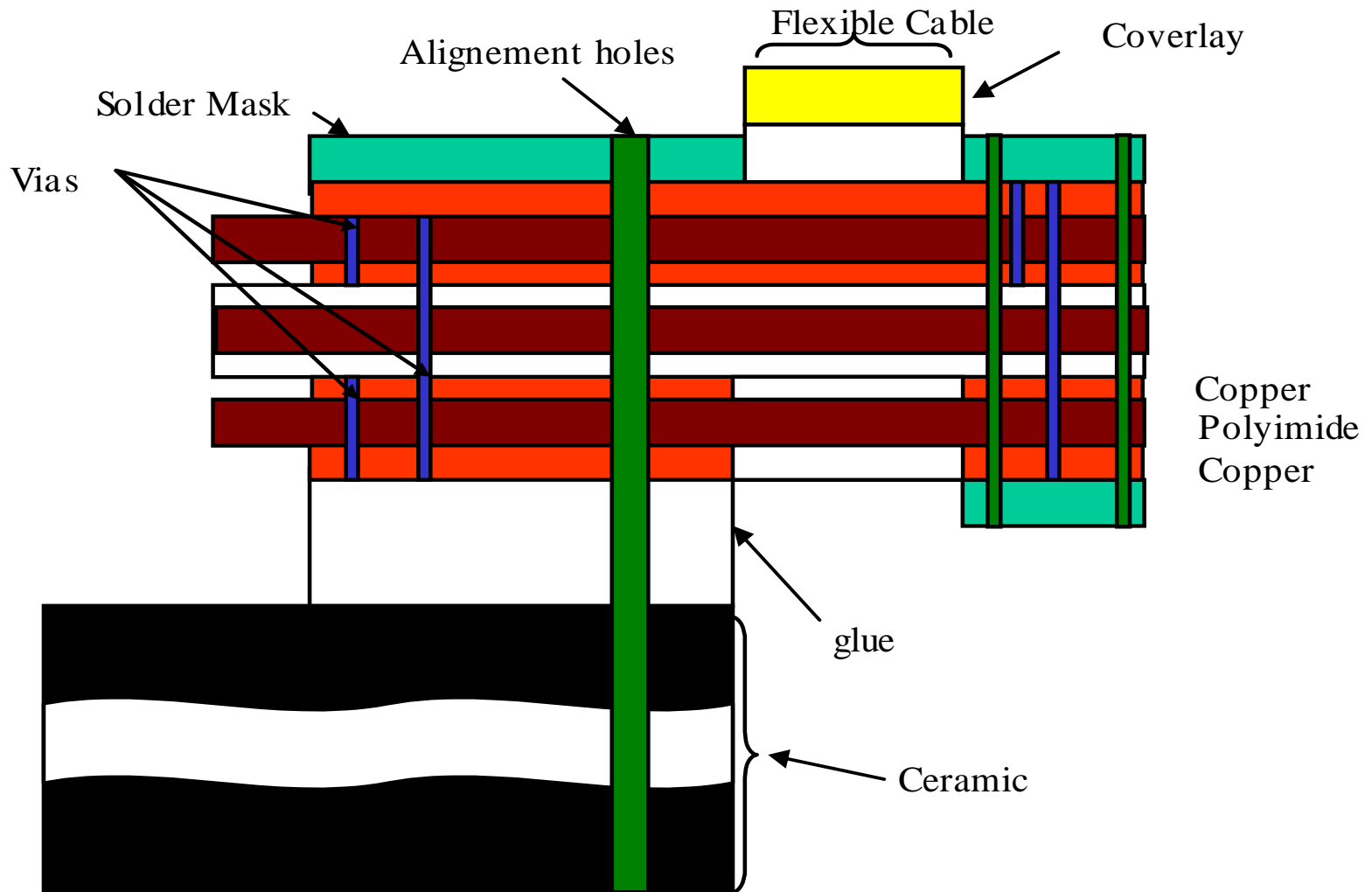


November 2011

Hybrid Quality Issues for Present LHC Trackers:  
The CMS Example

Marcello Mannelli

# *The Hybrid Layup*





# *Technological difficulties, circuit*

- Metal on flex
- Lamination on ceramic
- Via metallization
  - Hidden defect
- Fast production / Slow QA feedback
- Irreversible addition of value when mounting hybrid on sensor module
- Large effort to recover

